



Traceability North America TC Chapter

Meeting Summary and Minutes

Fall 2018 Meeting

November 8, 2018 15:30 – 17:00

Milpitas, California

TC Chapter Announcements

Next TC Chapter Meeting

April 4, 2019 at 12:30 – 14:00

SEMI HQ, Milpitas, CA

Table 1 Meeting Attendees

Italics indicate virtual participants

Co-Chairs: Yaw Obeng (NIST); Win Baylies (BayTech Resor)

SEMI Staff: Inna Skvortsova

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
NIST	<i>Obeng</i>	<i>Yaw</i>	Siemens-Mentor Graphics	Waterworth	Janice
PEER	Fuchigami	Albert	Daewon SPIC	Lie	Jonathan
PDF Solutions	Huntley	David	Multibeam Corp	Prescor	Ted
<i>Samsung</i>	<i>Bruce</i>	<i>Eric</i>	Multibeam Corp	Lam	David
Cisco	Conroy	Zoe	SEMI	Skvortsova	Inna
Infras-Advisors	Leckie	Ron			

Table 2 Leadership Changes

<i>WG/TF/SC/TC Name</i>	<i>Previous Leader</i>	<i>New Leader</i>
None		

Table 3 Committee Structure Changes

<i>Previous WG/TF/SC Name</i>	<i>New WG/TF/SC Name or Status Change</i>
None	



Table 4 Ballot Results

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
6428	Reapproval to SEMI T3-1213, <i>Specification for Wafer Box Labels</i>	passed
6429	Reapproval to SEMI T4-0301 (Reapproved 1213), <i>Specification for 150 mm and 200 mm Pod Identification Dimensions</i>	passed
6450	New Standard – <i>Specification for Single Device Traceability for the Supply Chain</i>	passed with editorial changes

#1 **Passed** ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

#2 **Failed** ballots and line items were returned to the originating task forces for re-work and re-balloting or abandoning.

Table 5 Activities Approved by the GCS between meetings of the TC Chapter

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
6448	SNARF	EMT TF	New Standard – <i>Specification for Equipment and Materials Label</i>
6449	SNARF	EMT TF	New Standard – <i>Specification for Equipment and Materials Part Traceability</i>
6450	SNARF	SDT TF	New Standard – <i>Specification for Single Device Traceability for the Supply Chain</i>

Table 6 Authorized Activities

Listing of all revised or new SNARF(s) approved by the Originating TC Chapter.

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
6471	SNARF	SDT TF	Line Item Revision to New Standard (designation TBD)– <i>Specification for Single Device Traceability for the Supply Chain</i> New SNARF approved at TC meeting

#1 SNARFs and TFOFs are available for review on the SEMI Web site at:

<http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF>

Table 7 Authorized Ballots

<i>#</i>	<i>When</i>	<i>TF</i>	<i>Details</i>
None			

Table 8 SNARF(s) Granted a One-Year Extension

<i>#</i>	<i>TF</i>	<i>Title</i>	<i>Expiration Date</i>
None			

Table 9 SNARF(s) Abolished

<i>#</i>	<i>TF</i>	<i>Title</i>
None		

Table 10 Standard(s) to receive Inactive Status

<i>Standard Designation</i>	<i>Title</i>
None	



Table 11 New Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
NONE		

Table 12 Previous Meeting Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
NONE		

1 Welcome, Reminders, and Introductions

Yaw Obeng (NIST) called the meeting to order at 15:36PM. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

Attachment 01: SEMI Standards Required Elements.ppt

2 Review of Previous Meeting Minutes

2.1 The TC Chapter reviewed and approved the minutes of the previous SEMICON West 2018 Standards meeting.

Motion: To approve minutes as written

By / 2nd: Dave Huntley (PDF Solutions) / Ron Leckie (Infras-Advisors)

Discussion: None

Vote: 8/0. Motion passed.

Attachment 02: NA Traceability TC Meeting Minutes (July 2018).pdf

3 SEMI Standards Staff Report

3.1 Inna Skvortsova (SEMI) gave the SEMI Staff Report. Of note:

SEMI Global 2018 Calendar of Events

- o SEMICON Europa (November 13-16, 2018, Munich, Germany)
- o SEMICON Japan (December 12-14, 2018, Tokyo, Japan)

SEMI Global 2019 Calendar of Events

- o SEMICON Korea (January 23-25, 2019), Seoul, Korea
- o MEMS and Sensor Industry Group (February 19-20, Monterey, California)
- o SEMICON China (March 20-22, Shanghai, China)
- o SEMICON Southeast Asia (May 7-9, Kuala Lumpur, Malaysia)
- o SEMICON West (July 9-11, San Francisco, California)

Upcoming North America Meetings

- o NA Standards Spring 2019 Meetings (April 1-4, 2019, SEMI HQ, Milpitas, California)
- o SEMICON West 2019 Meetings (July 8-11, 2019, San Francisco, California)
- o NA Standards Fall 2019 Meetings (November 4-7, 2019, SEMI HQ, Milpitas, California)

Letter Ballot Critical Dates for NA Standards meetings

- o Cycle 8-18: due Oct 12 / Voting Period: Oct 26 – Nov 26



- Cycle 9-18: due Nov 14/ Voting Period: Nov 28 – Dec 28
- Cycle 1-19: due Jan 3 / Voting Period: Jan 16 – Feb 16
- Cycle 2-19: due Feb 1 / Voting Period: Feb 15 – March 18
- Cycle 3-19: due March 12 / Voting Period: March 26-April 25

<http://www.semi.org/en/Standards/Ballots>

• SEMI Standards Publications

Cycle	New	Revised	Reapproved	Withdrawn
July 2018	0	3	21	0
August 2018	2	11	4	0
September 2018	0	8	1	0
October 2018	7	8	12	0

Total SEMI Standards in portfolio: 996. Includes 252 Inactive Standards

Cycle	Designation	Title	Committee	Region
October 2018	SEMI PV85	Practice for Metal Wrap Through (MWT) Back Contact Photovoltaic (PV) Module Assembly	Photovoltaic	CH
October 2018	SEMI PV86	Specification for Crystalline Silicon Photovoltaic Module Dimensions	Photovoltaic	CH
October 2018	SEMI PV87	Test Method for Peeling Force Between Electrode and Ribbon/Back Sheet	Photovoltaic	CH
October 2018	SEMI PV88	Test Method for Determination of Hydrogen in Photovoltaic (PV) Polysilicon by Inert Gas Fusion Infrared Absorption Method	Photovoltaic	CH

- New Forms, Regulations & Procedure Manual
 - New version of *Regulations* (June 8, 2018)
 - New version of *Procedure Manual* (June 8, 2018)
 - New TFOF & SNARF
 - New Ballot Review Templates
 - www.semi.org/standards



- Bottom left, under **Resources!**
- Rules for Handling of Trademark (Regulations § 16.4)
 - Sections 16.4.1 and 16.4.4 of the recently revised of the Regulations contain requirements for the use of trademarks in published Documents.
 - Existing Documents have been found that contain trademarks for items such as materials, software protocols, and equipment.
 - All TC Chapters should review their Documents **at the time a revision or reapproval ballot** is planned to determine if a trademark is used and, if so, whether its use is justified, properly represented, and that a footnote references the trademark owner.
 - Failure to do so could jeopardize ballot approval.
- *SNARF(s) and TFOF Approved by GCS in between TC Chapter Meetings*
 - SNARF for New Standard – Specification for Equipment and Materials Label
 - SNARF#6448
 - Authorized by GCS 8/22/2018
 - SNARF for New Standard – Specification for Equipment and Materials Part Traceability
 - SNARF#6449
 - Authorized by GCS 8/22/2018
 - SNARF for New Standard – Specification for Single Device Traceability for the Supply Chain;
 - SNARF#6450 & ballot submission for Cycle 7-2018
 - Authorized by GCS 8/22/2018
- *SNARF 3 year status TC Chapter may grant a one-year extension:*
 - **None**
- *SNARFs to abolish at I&C TC meeting:*
 - **None**
- *Nonconforming Titles*
 - **None**

NOTE: Refer to Procedure Manual (PM) Appendix Table A4-1 and A4-2

- *Documents due for 5 Year Review*

Name	Due for Review	Title
SEMI T3-1213	12/13/2018	Specification for Wafer Box Labels. Ballot passed.
SEMI T4-0301 (Reapproved 1213)	12/13/2018	Specification for 150 mm and 200 mm Pod Identification Dimensions. Ballot passed.
SEMI T11-0703 (Reapproved 1014)	10/30/2019	Specification for Marking of Hard Surface Reticle Substrates

Attachment 03: SEMI Standards Staff Report Traceability TC Nov 2018.ppt



4 Liaison Reports

4.1 Traceability Japan TC Chapter

Inna Skvortsova (SEMI) reported for the Traceability Japan TC Chapter. Of note:

- Meeting Information
 - Last meeting: December 15, 2017 at the SEMICON Japan 2017 Standards Meetings, Tokyo Big Sight, Tokyo, Japan
 - Next meeting: December 12, 2018 at the SEMICON Japan 2018 Standards Meetings, Tokyo Big Sight, Tokyo, Japan
- Traceability Japan TC Chapter Leadership (no changes)
 - Yoichi Iga (Toshiba)
 - Hirokazu Tsunobuchi (Keyence)
- Announcements
 - Workshop for Traceability Standards Activities to Support Supply Chain Integration
 - Date & Time: Wed, December 12, 11:00-12:40
 - Venue: Conference Tower, Tokyo Big Sight, Tokyo, Japan
 - Items in the program:
 - Opening remarks by Japan TC Chapter co-chair (Yoichi Iga / Toshiba)
 - (Single Device Traceability TF) Explanation of Ballot #6450 by Dave Huntley / PDF Solutions
 - (Equipment & Materials Traceability TF) Explanation of Document #6448 / #6449 by Doug Suerich / The Peer Group
 - Q&A and exchanging ideas with participants
 - Closing remarks by Japan TC Chapter co-chair (Hirokazu Tsunobuchi / Keyence)
- Ballot Results

Doc #	Document Title	TC Chapter Action
6203	Reapproval of SEMI T22-0212: "Specification for Traceability by Self Authentication Service Body and Authentication Service Body"	Passed , as balloted
6244*	Reapproval of SEMI T10-0701 (Reapproved 0912): "Test Method For The Assessment Of 2d Data Matrix Direct Mark Quality"	Passed , as balloted
6246*	Reapproval of SEMI T17-0706 (Reapproved 0812): "Specification Of Substrate Traceability"	Passed , as balloted
6247*	Reapproval of SEMI T18-1106 (Reapproved 0812): "Specification of Parts And Components Traceability"	Passed , as balloted
6293	Line Item Revision to SEMI T15-0812: "General Specification of Jig ID: Concept" with title change to "Specification for Jig ID: Concept"	/
Line Item 1	Change nonconforming title	Passed , as balloted
Line Item 2	Add section title to meet the requirement which is specified section 3.2 of Procedure Manual	Passed , with editorial changes

NOTE: *marked document are originated from North America.



- Activities Approved via GCS between Meetings

Doc #	Type	SC/TF/CFG	Title/Details
6293	SNARF and Ballot Submission	5 Year Review TF	Line Item Revision to SEMI T15-0812 "General Specification of Jig ID: Concept" with non-conforming title change to "Specification for Jig ID: Concept" – Approved and authorized for ballot in voting Cycle 8-2017 by GCS on 10/13/2017
6245	Withdrawal of SNARF	5 Year Review TF under NA TC Chapter	Reapproval of SEMI T15-0812, General Specification Of Jig Id: Concept – Prepared by the 5 Year Review Task Force, under the Traceability North America TC Chapter. During the preparation of the ballot draft of Reapproval of SEMI T15-0812, it was found out that the document was originally developed by the Traceability Japan TC Chapter and also needs some corrections. So, a new SNARF for Line Item Revision to SEMI T15-0812 is proposed by the Japan TC Chapter as above. – Approved by GCS on 10/13/2017

- Authorized Activities

- None

- Authorized Ballots

- None

- Abolished SNARF(s)

- None

- Documents due for 5-Year Review

Designation	Standard Title	Action By	Assigned to
SEMI T21-0314	Specification for Organization Identification by Digital Certificate Issued from Certificate Service Body (CSB) for Anti-Counterfeiting Traceability in Components Supply Chain	Spring 2019	5 Year Review TF

- Task Force Highlights

- None

- For additional information, please contact SEMI Japan staff:

- Chie Yanagisawa cyanagisawa@semi.org

Attachment 04: Japan Traceability TC Report (Nov 2018).ppt

5 Ballot Review

NOTE 1: TC Chapter adjudication on ballots reviewed is detailed in the Audits & Review (A&R) Subcommittee Forms for procedural review. The A&R forms are available as attachments to these minutes. The attachment number for each balloted document is provided under each ballot review section below.

5.1 Ballot #6428

The TC Chapter reviewed the Document #6428, Reapproval to SEMI T3-1213, *Specification for Wafer Box Labels*

The ballot **passed** TC review as balloted and will be submitted to the ISC A&R for procedural review. Details can be found in the attached Procedural Review file.



Motion: Document # 6428 is not a Safety Document, when all safety-related information is removed, Document is still technically sound and complete.

By / 2nd: Albert Fuchigami (PEER Group) / Dave Huntley (PDF Solutions)

Discussion: None.

Vote: 8-0. Motion passed.

Motion: Forward Document # 6428 to the ISC A&R for procedural review as balloted.

By / 2nd: Albert Fuchigami (PEER Group) / Dave Huntley (PDF Solutions)

Discussion: None.

Vote: 8 -0. Motion passed.

Attachment 05: 6428_Procedural Review

5.2 Ballot #6429

The TC Chapter reviewed the Document #6429, Reapproval to SEMI T4-0301 (Reapproved 1213), *Specification for 150 mm and 200 mm Pod Identification Dimensions*

The ballot **passed** TC review as balloted and will be submitted to the ISC A&R for procedural review. Details can be found in the attached Procedural Review file.

Motion: Document # 6429 is not a Safety Document, when all safety-related information is removed, Document is still technically sound and complete.

By / 2nd: Albert Fuchigami (PEER Group) / Dave Huntley (PDF Solutions)

Discussion: None.

Vote: 8-0. Motion passed.

Motion: Forward Document # 6429 to the ISC A&R for procedural review as balloted.

By / 2nd: Albert Fuchigami (PEER Group) / Dave Huntley (PDF Solutions)

Discussion: None.

Vote: 8 -0. Motion passed.

Attachment 06: 6429_Procedural Review

5.3 Ballot #6450

The TC Chapter reviewed the Document #6450, New Standard – *Specification for Single Device Traceability for the Supply Chain*

The ballot **passed** TC review with editorial changes and will be forwarded to the ISC A&R SC for procedural review. Details can be found in the attached Procedural Review file.

Motion: Document # 6450 is not a Safety Document, when all safety-related information is removed, Document is still technically sound and complete.

By / 2nd: Albert Fuchigami (PEER Group) / Dave Huntley (PDF Solutions)

Discussion: None.

Vote: 8-0. Motion passed.

Motion: Forward Document # 6450 to the ISC A&R for procedural review as balloted.

By / 2nd: Albert Fuchigami (PEER Group) / Dave Huntley (PDF Solutions)

Discussion: None.

Vote: 8 -0. Motion passed.

Attachment 07: 6450_Procedural Review

6 Subcommittee and Task Force Reports

6.1 Single Device Traceability (SDT) Task Force Report

Dave Huntley (PDF Solutions) reported for the SDT Task Force. Of note:

- Leadership Change
 - None
- Ballot Adjudication (expected to pass with editorial changes)
 - 6450, New Standard: Specification for Single Device Traceability for the Supply Chain
- New SNARF(s)
 - Line Item Revision to New Standard (designation TBD)– Specification for Single Device Traceability for the Supply Chain
 - To incorporate technical feedback received during balloting doc #6450
- Upcoming work - proposal for new anticounterfeiting Standard
 - SNARF authorization planned for Spring 2019 Standards Meetings or earlier via GCS
 - To evaluate T21 as related to new proposed standard for anticounterfeiting
- Educational Workshop - will present SDT TF purpose and ballot proposals along with EMT TF at SEMICON Japan 2018

Attachment 08: SDT Task Force report Nov. 2018.PPT

6.2 Equipment and Materials Traceability (EMT) Task Force Report

Albert Fuchigami (PEER Group) and Eric Bruce (Samsung) reported for the EMT Task Force. Of note:

- Leadership Change / Ballot Adjudication / New SNARF(s)
 - None
- Upcoming ballots (Spring 2019 Meetings)
 - 6448 - New Standard: Specification for Equipment and Materials Part Labels
 - 6449 - New Standard: Specification for Equipment and Materials Part Traceability
- Ongoing work on draft Ballots – focusing on #6448 first
 - Look at IDM requirements as a starting point
 - What needs to be supported for ‘grandfathered’ requirements.



- What needs to be handled forward looking
- Looking for other IDM input (Specifically someone at Intel - they have lots of existing standards related to topic – example RossettaNet)
Would like to make sure their requirements are incorporated.
- Looking for contacts who etches parts to understand best practices.
(2D identifications)
- Educational Workshop- will present EMT TF purpose and ballot proposals along with SDT TF at SEMICON Japan 2018

Attachment 09: EMT TF Report Nov 2018.PPT

6.3 Traceability Five Year Review Task Force Report

- No report presented at TC. Upcoming activities of note:
 - SEMI T11-0703, *Specification for Marking of Hard Surface Reticle Substrates*
 - Review planned at SEMICON West 2019

7 Old Business

7.1 Standards due for Five-Year Review.

Inna Skvortsova addressed the TC Chapter on this topic. Of note:

Name	Due for Review	Title	Status
SEMI T11-0703 (Reapproved 1014)	10/30/2019	Specification for Marking of Hard Surface Reticle Substrates	To be reviewed by 5Yr Review TF at SEMICON West 2019

7.2 SNARFs Approaching 3-Year Review

The TC Chapter reviewed SNARFs approaching 3-year project period.

- No SNARFs received extended period.

8 New Business

8.1 New TFOFs Approval

- None

8.2 New SNARFs Approval

TC Chapter reviewed and approved draft SNARF(s) for Line Item Revision to New Standard (designation TBD)–*Specification for Single Device Traceability for the Supply Chain*, prepared by SDT Task Forces

Motion: Move to approve new SNARF for Line Item Revision to New Standard (designation TBD)–*Specification for Single Device Traceability for the Supply Chain*

By / 2nd: Dave Huntely (PDF Solutions) / Ron Leckie (Infras-Advisors)

Discussion: None.

Vote: 8/0. Motion passed.



8.3 New Ballots Authorization:

- None

9 Action Items Review

9.1 Previous Meeting(s) Action Items

Inna Skvortsova (SEMI) reviewed open action items. These can be found in the Previous Meeting(s) Action Items table at the beginning of these minutes.

9.2 New Action Items

Inna Skvortsova (SEMI) reviewed the new action items. These can be found in the New Action Items table at the beginning of these minutes.

10 Next Meeting and Adjournment

The next meeting is tentatively scheduled for April 4, 2019 at SEMI HQ, Milpitas, CA. See <http://www.semi.org/en/events> for the current list of meeting schedules.

Having no further business, a motion was made to adjourn. Adjournment was at 4:46PM.

Respectfully submitted by:

Inna Skvortsova
Sr. Standards Coordinator
SEMI North America
Phone: 408-9436996
Email: iskvortsova@semi.org

Minutes tentatively approved by:

Yaw Obeng (NIST)	1/29/2019
Winthrop Baylies (BayTech Resor)	

Table 13 Index of Available Attachments#1

<i>Title</i>	<i>Title</i>
Attachment 01: SEMI Standards Required Elements.ppt	Attachment 06: 6429 Procedural Review
Attachment 02: NA Traceability TC Meeting Minutes (July 2018)	Attachment 07: 6450 Procedural Review
Attachment 03: SEMI Standards Staff Report (Nov 2018)	Attachment 08: SDT Task Force Report (Nov 2018)
Attachment 04: Japan Liaison Report (Nov 2018).pdf	Attachment 09: EMT Task Force Report (Nov 2018)
Attachment 05: 6428 Procedural Review	

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact Inna Skvortsova at the contact information above.